

OptiMOS™ -T Power-Transistor



Features

- N-channel - Enhancement mode
- AEC qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

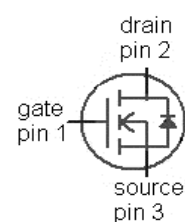
Product Summary

V_{DS}	250	V
$R_{DS(on),max}$	100	mΩ
I_D	17	A

PG-TO263-3-2

PG-TO220-3-1


Type	Package	Marking
IPB17N25S3-100	PG-TO263-3-2	3N25100
IPP17N25S3-100	PG-TO220-3-1	3N25100



Maximum ratings, at $T_j=25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	$T_C=25^\circ\text{C}$, $V_{GS}=10\text{ V}$	17	A
		$T_C=100^\circ\text{C}$, $V_{GS}=10\text{V}^{1)}$	13.3	
Pulsed drain current ¹⁾	$I_{D,pulse}$	$T_C=25^\circ\text{C}$	68	
Avalanche energy, single pulse ¹⁾	E_{AS}	$I_D=5.4\text{ A}$	54	mJ
Avalanche current, single pulse	I_{AS}	-	5.4	A
Reverse diode dv/dt	dv/dt	-	6	kV/ μs
Gate source voltage	V_{GS}	-	± 20	V
Power dissipation	P_{tot}	$T_C=25^\circ\text{C}$	107	W
Operating and storage temperature	T_j , T_{stg}	-	-55 ... +175	$^\circ\text{C}$
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Thermal characteristics¹⁾

Thermal resistance, junction - case	R_{thJC}	-	-	-	1.4	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	-	62	
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ²⁾	-	-	40	

Electrical characteristics, at $T_j=25^\circ\text{C}$, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=1mA$	250	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=54\mu A$	2.0	3.0	4.0	
Zero gate voltage drain current	I_{DSS}	$V_{DS}=250V, V_{GS}=0V$	-	0.01	1	μA
		$V_{DS}=250V, V_{GS}=0V, T_j=125^\circ\text{C}^{2)}$	-	1	100	
Gate-source leakage current	I_{GSS}	$V_{GS}=20V, V_{DS}=0V$	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=17A$	-	85	100	m Ω

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic characteristics¹⁾

Input capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=25V,$ $f=1MHz$	-	1133	1500	pF
Output capacitance	C_{oss}		-	480	625	
Reverse transfer capacitance	C_{rss}		-	11	23	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=125V, V_{GS}=10V,$ $I_D=17A, R_G=3.3\Omega$	-	4.4	-	ns
Rise time	t_r		-	3.7	-	
Turn-off delay time	$t_{d(off)}$		-	7.5	-	
Fall time	t_f		-	1.2	-	

Gate Charge Characteristics^{1), 3)}

Gate to source charge	Q_{gs}	$V_{DD}=200V, I_D=17A,$ $V_{GS}=0 \text{ to } 10V$	-	5	7	nC
Gate to drain charge	Q_{gd}		-	2.4	4.8	
Gate charge total	Q_g		-	14	19	
Gate plateau voltage	$V_{plateau}$		-	4.6	-	V

Reverse Diode

Diode continuous forward current ¹⁾	I_S	$T_C=25^\circ C$	-	-	17	A
Diode pulse current ¹⁾	$I_{S,pulse}$		-	-	56	
Diode forward voltage	V_{SD}	$V_{GS}=0V, I_F=17A,$ $T_j=25^\circ C$	-	0.9	1.3	V
Reverse recovery time ¹⁾	t_{rr}	$V_R=125V, I_F=17A,$ $di_F/dt=100A/\mu s$	-	120	-	ns
Reverse recovery charge ¹⁾	Q_{rr}		-	525	-	nC

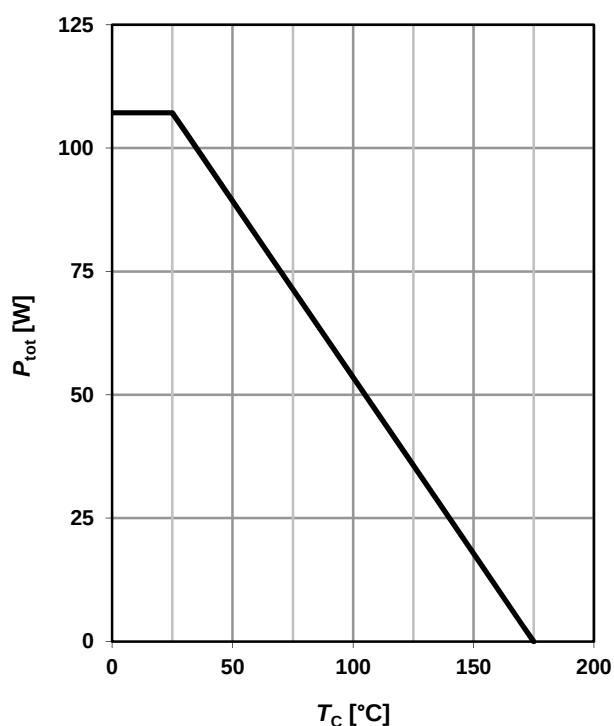
¹⁾ Defined by design. Not subject to production test.

²⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

³⁾ Devices thermal performance determined according to EIA JESD 51-14
"Transient Dual Interface Test Method For The Measurement Of The Thermal Resistance"

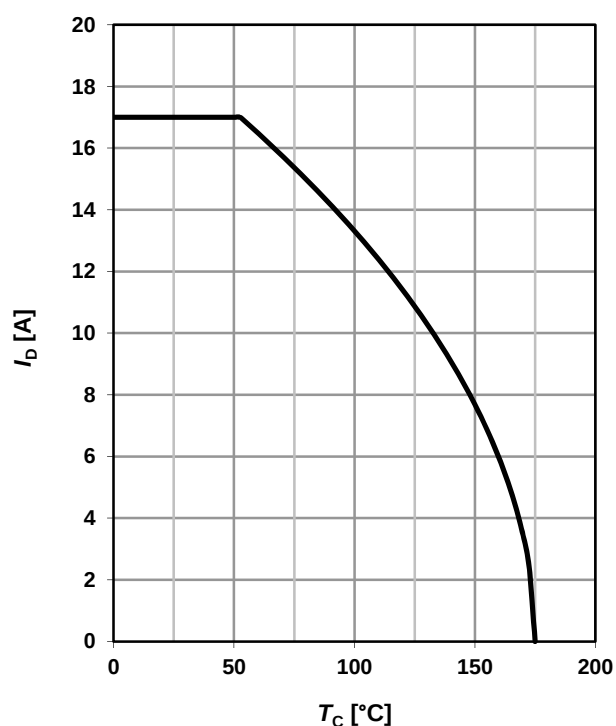
1 Power dissipation

$$P_{\text{tot}} = f(T_C); V_{\text{GS}} \geq 6 \text{ V}$$



2 Drain current

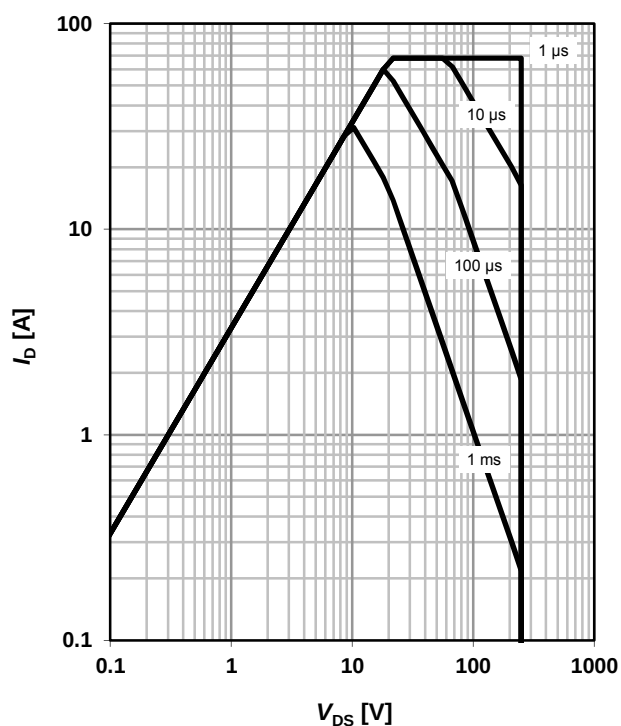
$$I_D = f(T_C); V_{\text{GS}} \geq 6 \text{ V}; \text{SMD}$$



3 Safe operating area

$$I_D = f(V_{\text{DS}}); T_C = 25 \text{ °C}; D = 0; \text{SMD}$$

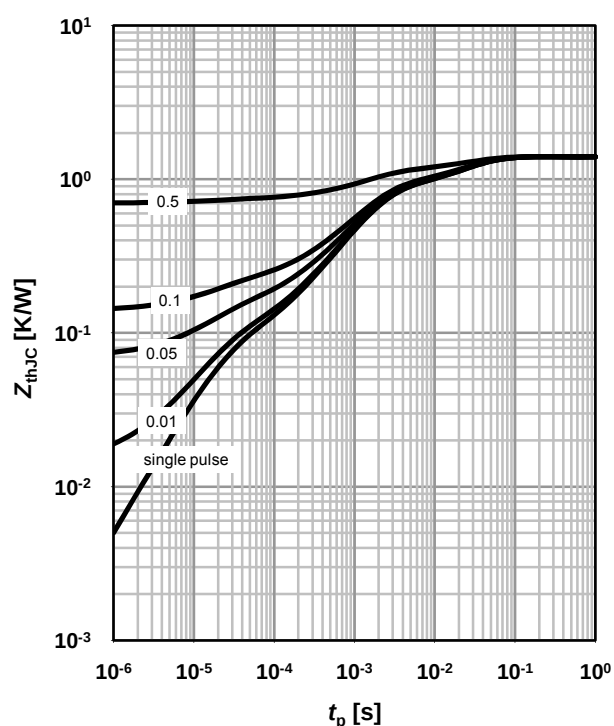
parameter: t_p



4 Max. transient thermal impedance

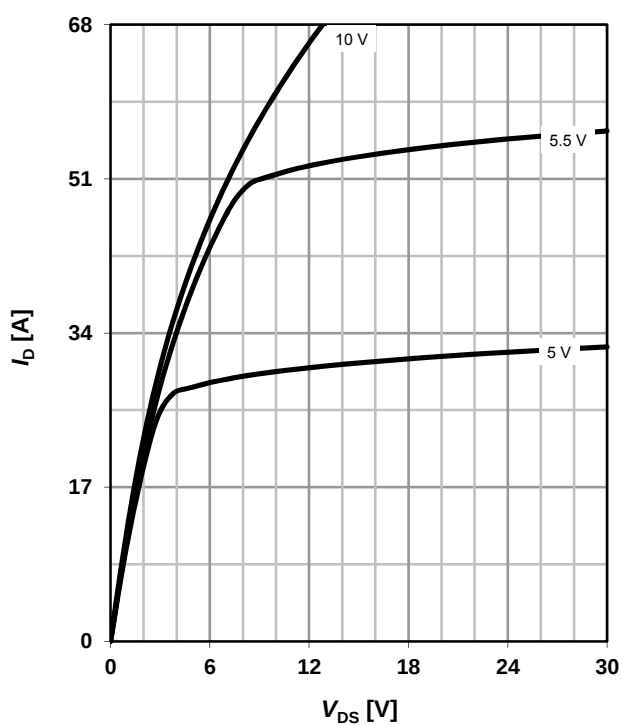
$$Z_{\text{thJC}} = f(t_p)$$

parameter: $D = t_p/T$



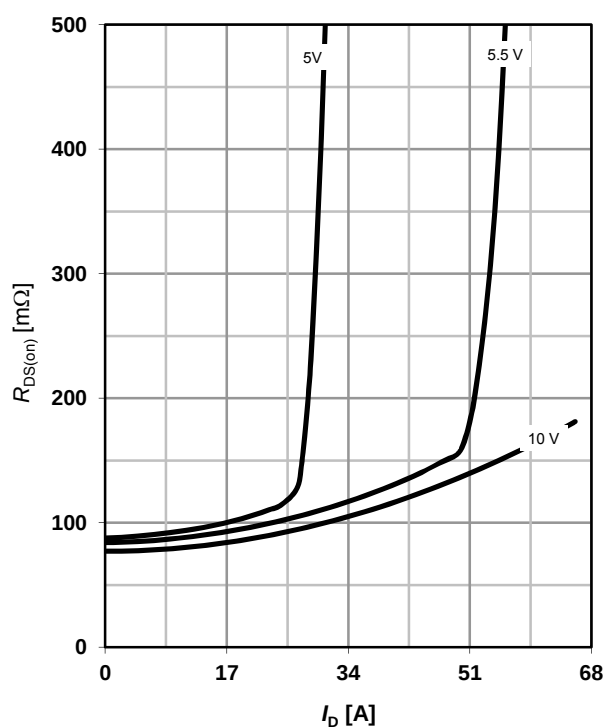
5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25\text{ °C}; \text{SMD}$

parameter: V_{GS}


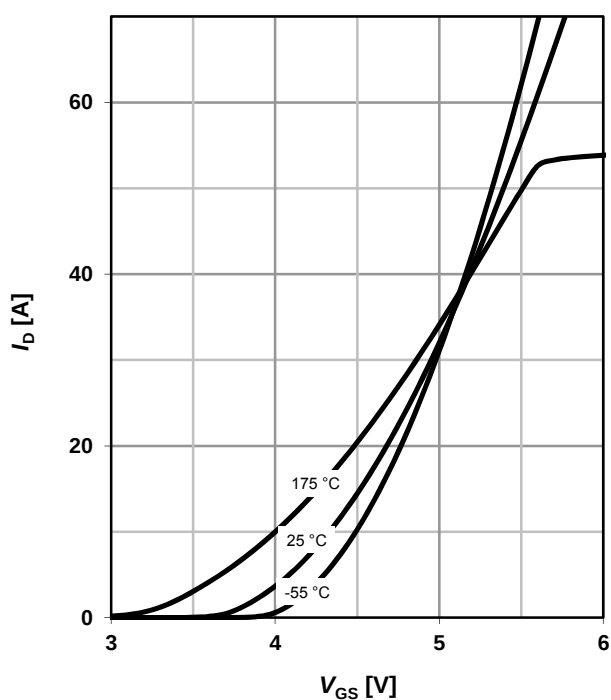
6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25\text{ °C}; \text{SMD}$

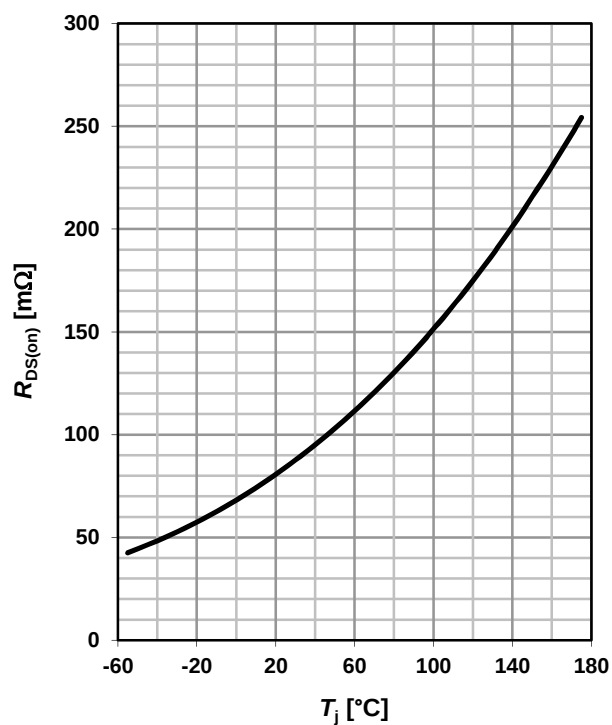
parameter: V_{GS}


7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 25\text{ V}$

parameter: T_j


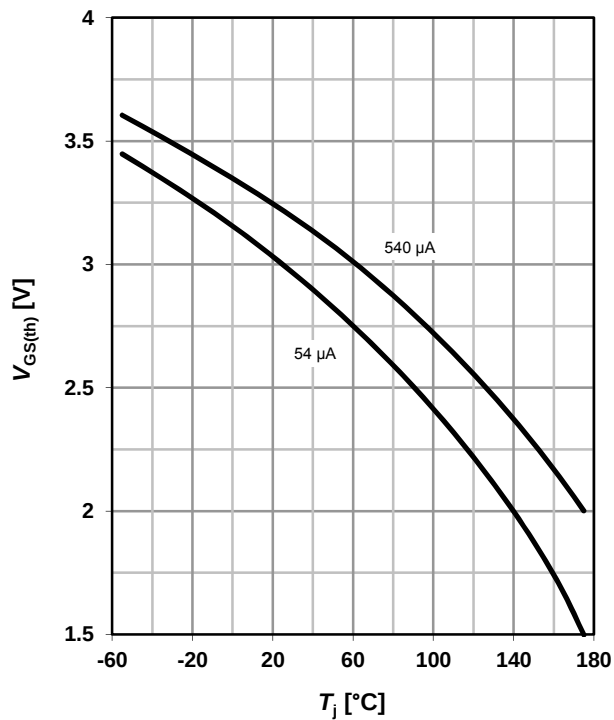
8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j); I_D = 17\text{ A}; V_{GS} = 10\text{ V}; \text{SMD}$


9 Typ. gate threshold voltage

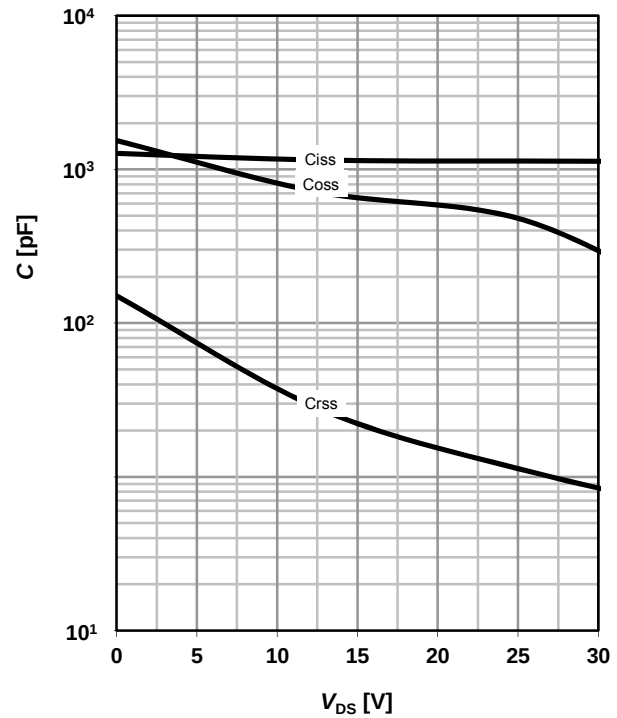
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

parameter: I_D



10 Typ. capacitances

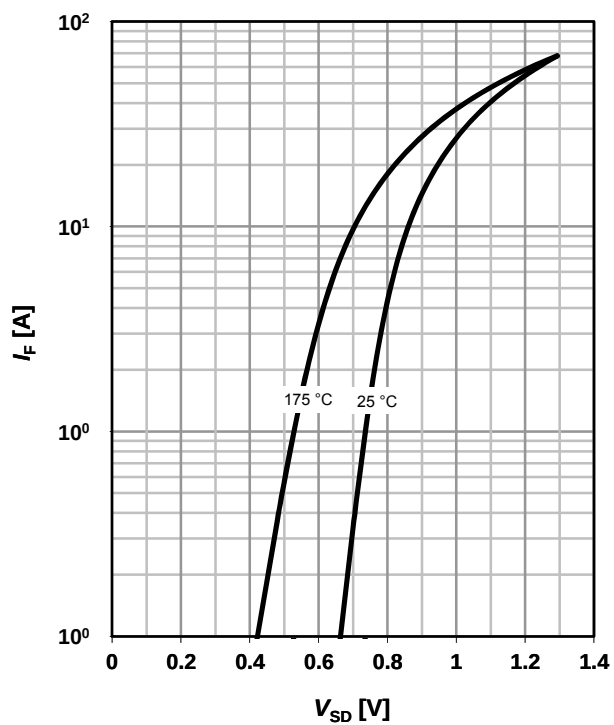
$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$



11 Typical forward diode characteristics

$$I_F = f(V_{SD})$$

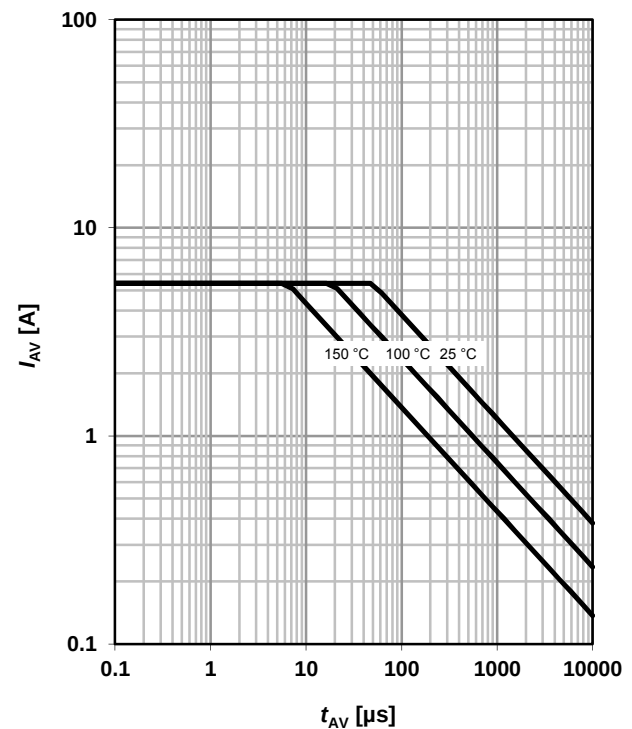
parameter: T_j



12 Avalanche characteristics

$$I_{AS} = f(t_{AV})$$

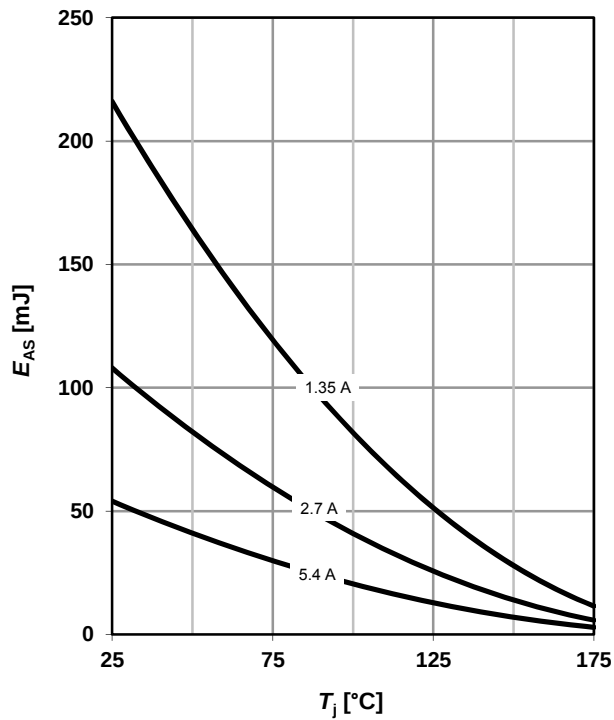
parameter: $T_{j(start)}$



13 Avalanche energy

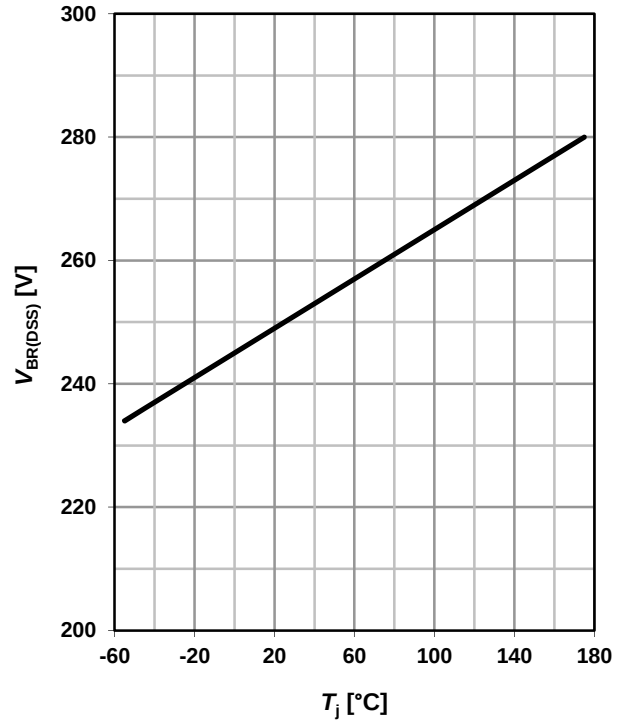
$$E_{AS} = f(T_j)$$

parameter: I_D



14 Drain-source breakdown voltage

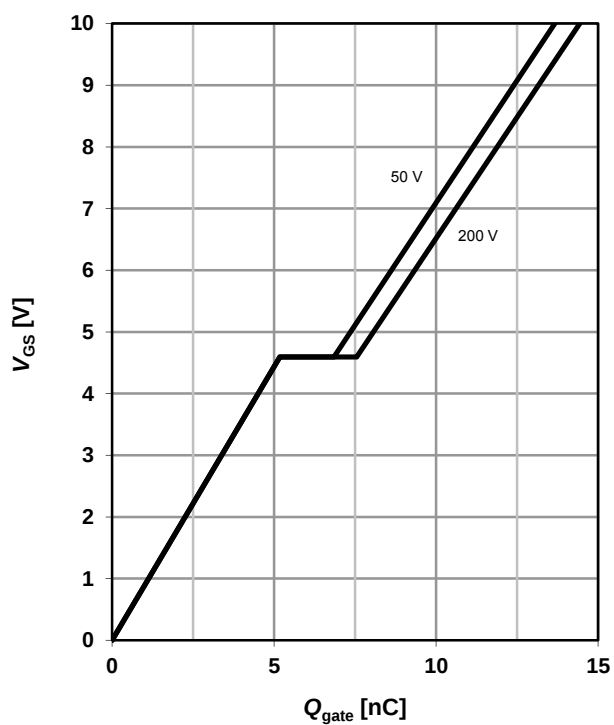
$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$



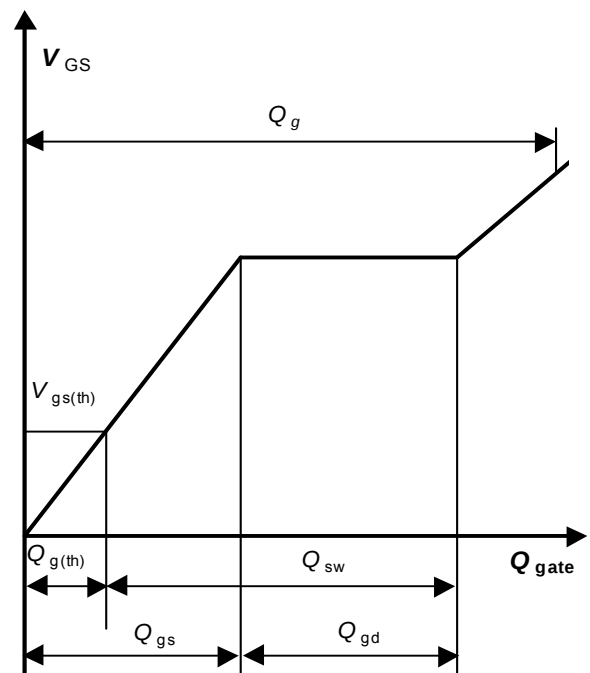
15 Typ. gate charge

$$V_{GS} = f(Q_{gate}); I_D = 17 \text{ A pulsed}$$

parameter: V_{DD}



16 Gate charge waveforms



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Revision History

Version	Date	Changes
Revision 1.0	18.10.2012	Final Data Sheet
Revision 1.1	12.05.2013	Update of diagram 5 and 6